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THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant TAEYOUNG HAN et al

Art Unit 1762

Attorney Docket Number DP-310179

Serial 10/808245  
No.

Filed March 24, 2004

Title KINETIC SPRAY NOZZLE SYSTEM DESIGN

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Lowell M. Train

STATEMENT ACCOMPANYING  
INFORMATION DISCLOSURE STATEMENT

Applicant(s) requests the Examiner to consider and make of record the reference(s) and/or information on attached PTO 1449.

**CHECK ONE: (A, B, or C.)**

☐ A. This statement is submitted within 1) three months after the filing date (even if after the first action); or 2) within three months of the date of entry of the national stage or 3) before the mailing date of a first Office Action. No fee or statement is required.

☐ B. This statement is submitted after the period specified in para. A, but before Final Office Action or Notice of Allowance or the close of prosecution.

**CHECK ONE: (1, 2, or 3)**

☐ 1. I hereby state that each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or

☐ 2. I hereby state that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in § 1.56 (c) more than three months prior to the filing of the information disclosure statement.

☐ 3. Charge the fee set forth in § 1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

☒ C. This statement is submitted after a Final Office Action or Notice of Allowance or the close of prosecution, but before payment of the issue fee. Charge the fee set forth in § 1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

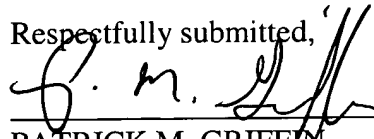
**CHECK ONE: (1 or 2)**

☐ 1. I hereby state that each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or

☐ 2. I hereby state that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in § 1.56 (c) more than three months prior to the filing of the information disclosure statement.

**REMARKS UNDER 1.98 (a)(3)**

Please consider the attached reference(s) which have come to the attention of Applicants since the last submission of an IDS. If any fee should be required, please charge the appropriate fee to Delphi Technologies, Inc. Deposit Account No. 50-0831.

Respectfully submitted,  
  
PATRICK M. GRIFFIN  
CUSTOMER NUMBER 22851  
Reg. No: 29,716  
Telephone (248) 813-1215

Enclosure: PTO 1449

**INFORMATION DISCLOSURE CITATION WITH DOCUMENT COPIES**

Submitted by:

SCOTT A. MCBAIN  
CUSTOMER NUMBER 22851  
Delphi Technologies, Inc.,

Reg. No. 37181

Atty. Docket No.  
DP-310179

Serial No.  
10/808245

Applicant  
Taeyoung Han.

Filing Date  
March 24, 2004

Group  
1762

**U.S. PATENT DOCUMENTS**

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Examiner

|Date Considered

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SCOTT A. MCBAIN CUSTOMER NUMBER 22851 Delphi Technologies, Inc.,	Applicant Taeyoung Han	
Reg. No. 37181	Filing Date 03-24-2004	Group 1762

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	03/24/2004	1762

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**Form PTO-FB-A820 (also PTO-1449) Patent & Trademark Office-US Dept. of Commerce**

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Document Number	Date	Country	Class	Subclass	Translation Yes   No

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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No

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